

<b>Notice of References Cited</b>	Application/Control No. 09/785,413		Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Justin P. Misleh		Art Unit 2612	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,525,761 B2	02-2003	Sato et al.	348/14.04
*	B	US-5,899,581 A	05-1999	Kawamura et al.	386/120
*	C	US-5,999,697	12-1999	Murase et al.	386/101
*	D	US-6,784,925 B1	08-2004	Tomat et al.	348/207.11
*	E	US-6,930,709 B1	08-2005	Creamer et al.	348/211.3
*	F	US-5,848,420 A	12-1998	Xu, Lin	707/104.1
*	G	US-6,889,364 B2	05-2005	Camara et al.	715/771
*	H	US-5,914,787 A	06-1999	Satoh et al.	358/402
*	I	US-6,698,021 B1	02-2004	Amini et al.	725/105
*	J	US-2002/0090208 A1	07-2002	HATANAKA, KOJI	386/117
*	K	US-6,947,075 B1	09-2005	Niikawa, Masahito	348/211.14
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.